

Bigeye

P-132 NIR



- Superior image quality
- Enhanced NIR sensitivity
- Peltier cooling -20°C

Bigeye P

Low noise CCD camera, Peltier cooling, up to 11 MP

Bigeye P-132 NIR 搭载 Sony ICX285 传感器，在 1.3 MP 分辨率下速度可达 12.5 帧/秒。

The Bigeye is a low noise CCD camera. It satisfies even the highest expectations for excellent image quality. The peltier cooling provides a superior signal-to-noise ratio even with very long exposure times. Bigeye NIR camera versions are designed for applications which require sensitivity both in the visible spectrum and the NIR spectrum.

- Sensitive Sony and OnSemi sensors, up to 11 Megapixels
- Peltier cooling for long exposure times
- Superior signal/noise ratio
- Robust metal housing for industrial use
- GigE Vision

性能参数

接口	IEEE 802.3 1000baseT
分辨率	1280 (H) × 1024 (V)
传感器	Sony ICX285
传感器类型	CCD Progressive
传感器尺寸	Type 2/3
像元尺寸	6.45 μm × 6.45 μm
标准镜头接口	C-Mount
最大满帧帧率	12.5 fps
ADC	14 Bit

输出

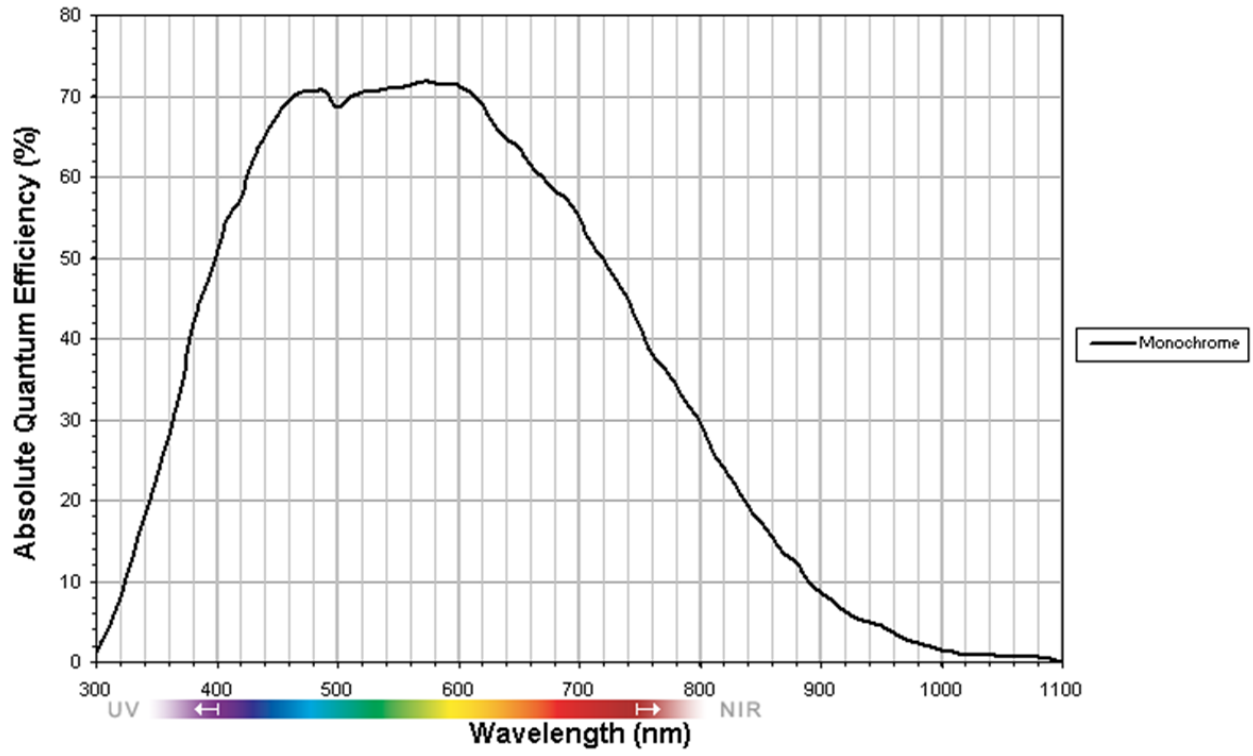
Bit 位数	12-bit
黑白像素格式	Mono8, Mono10, Mono12
原始像素格式	BayerGB8, BayerGB10, BayerGB12

通用输入输出口 (GPIOs)

工作条件/尺寸

工作温度	0 °C to +35 °C
电源要求 (DC)	12 V
功耗	33.6 W @ 12 VDC
重量	1410 g
尺寸 (L × W × H in mm)	111 × 90 × 99 (including connectors)

量子转换效率



特性

- Binning (2 x 2)
- Gain (6 dB)
- Exposure time 100 μ s to 1000 seconds
- Background correction
- Continuous mode (image acquisition with maximum frame rate)
- Image on demand mode (triggered image acquisition)

In combination with Allied Vision's AcquireControl software, extensive image analysis functions are available:

- BCG LUT (brightness, contrast, gamma)
- Auto contrast
- Auto brightness
- Analyze multiple regions (rectangular, circle) within the image
- Real-time statistics and histogram display

应用场景

The Bigeye P-132B NIR Cool is optimized for image acquisition both in the visible and in the NIR spectral range. For this reason, many applications can be realized with just one camera. Applications:

- Machine vision, visible and NIR spectrum
- Food inspection
- Medical and healthcare
- Microscopy
- Solar cell/wafer inspection, visible and NIR:
 - Glass inspection
 - Assembling inspection
 - Electroluminescence
 - Micro cracks detection
 - Defects
 - Efficiency